Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/809,181	SATOH ET AL.	
Examiner	Art Unit	
José R. Díaz	2815	

SEARCHED				
Class	Subclass	Date	Examiner	
257	669, 738,780, 787	3/28/2005	JRD	
257	E23.021	3/28/2005	JRD	
257	E23.069	3/28/2005	JRD	
257	E23.07	3/28/2005	JRD	
257	E23.123	3/28/2005	JRD	
257	E23.124	3/28/2005	JRD	
257	E23.133	3/28/2005	JRD	
174	52.2	3/28/2005	JRD	
174	52.3	3/28/2005	JRD	
438	123-124	3/28/2005	JRD	
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
257	669	3/28/2005	JRD		
257	738, 780	3/28/2005	JRD		
257	787	3/28/2005	JRD		
438/123-124					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Text Search: East (see attachment)	3/28/2005	JRD		